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APPLICATION NO.	F	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/750,042		12/30/2003	Wang Yuch	42P18259 9165	
8791	7590	12/14/2004		EXAMINER	
		OFF TAYLOR & 2 OULEVARD	WALKE, AMANDA C		
SEVENTH		*		ART UNIT	PAPER NUMBER
LOS ANG	LOS ANGELES, CA 90025-1030			1752	

DATE MAILED: 12/14/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)					
		10/750,042	YUEH ET AL.					
	Office Action Summary	Examiner	Art Unit					
	*	Amanda C Walke	1752					
Period fo	The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply							
THE I - Exter after - If the - If NO - Failu Any r	ORTENED STATUTORY PERIOD FOR REPLY MAILING DATE OF THIS COMMUNICATION. nsions of time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. period for reply specified above is less than thirty (30) days, a reply period for reply is specified above, the maximum statutory period were to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing and patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days fill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	ely filed s will be considered timely. the mailing date of this communication.					
Status		· ·						
	Responsive to communication(s) filed on <u>30 December 2003</u> . This action is FINAL . 2b) This action is non-final.							
3)□	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.							
Dispositi	on of Claims							
5)□ 6)⊠ 7)□	Claim(s) <u>1-28</u> is/are pending in the application. 4a) Of the above claim(s) is/are withdraw Claim(s) is/are allowed. Claim(s) <u>1-28</u> is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and/or							
Application	on Papers							
9) 🗆 -	The specification is objected to by the Examiner							
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.								
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).								
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.								
Priority u	nder 35 U.S.C. § 119							
a)[Acknowledgment is made of a claim for foreign part All b) Some * c) None of: 1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priorical application from the International Bureau ee the attached detailed Office action for a list of	have been received. have been received in Application ty documents have been received (PCT Rule 17.2(a)).	n Nod in this National Stage					
Attachment	(s)							
2) 🔲 Notice 3) 🔲 Inform	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) No(s)/Mail Date	4) Interview Summary (leader No(s)/Mail Date 5) Notice of Informal Pa	e					

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DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 2. Claims 1-28 are rejected under 35 U.S.C. 102(e) as being anticipated by Yoon et al (6,800,418).

Yoon et al disclose a fluorine – containing photosensitive polymer having hydrate structure and resist composition comprising the same. The photosensitive polymer having a structure to give a high transmittance at a F 2 excimer laser wavelength of 157 nm and good adhesion to an underlayer. It is another object of the present invention to provide a resist composition allowing development with conventional developers and having a high transmittance at a F 2 excimer laser wavelength of 157 nm (UV), good hydrophilicity, and good adhesion to an underlayer. According to an aspect of the present invention, a photosensitive polymer is provided having an average molecular weight of about 3,000-100,000 with a repeating unit including a structure meeting the instant claim limitations (see columns 4-10). The composition comprises a photoacid generator and it is preferable that the resist composition according to an embodiment of the present invention further comprises an organic base. In this case, the organic base may be contained in an amount of about 0.01-2.0% by weight based on the total weight of the photosensitive polymer. Preferably, the organic base comprises a single

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tertiary amine compound or a mixture of at least two ternary amine compounds. For example, the organic base may be triethylamine, triisobutylamine, triisooctylamine, triisodecylamine, diethanolamine, triethanolamine, or a mixture of these compounds.

It is preferable that the resist composition according to an embodiment of the present invention further comprises a surfactant of about 30-200 ppm. It is preferable that the resist composition according to an embodiment of the present invention further comprises a dissolution inhibitor of about 0.1-50% by weight based on the total weight of the photosensitive polymer. The composition is employed in a method comprising the steps of: dissolvinbg the polymer with triphenylsulfonium trifluoromethanesulfonate (triflate) as a photoacid generator (PAG) and triisodecylamine as an organic base. Each of the resist compositions was coated on a silicon wafer having an organic anti-reflective coating (ARC) to a thickness of about 0.15 microns. Each of the wafers coated with different resist compositions was soft-baked at a temperature of 100-140 degrees C for 60 seconds and exposed using an F 2 excimer laser stepper (NA=0.6). After the exposure process, the wafer was subjected to post-exposure bake (PEB) at a temperature of 110-140 degrees C for 60 seconds. The resultant wafer was subjected to development with a 2.38% by weight tetramethylammonium hydroxide (TMAH) solution, to form a resist pattern Given the teachings of the reference, the instant claims are anticipated by Yoon et al.

Conclusion

3. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Jung et al (6,391,518) and Harada et al (2003/0219678) are cited for their teachings of similar polymers.

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Any inquiry concerning this communication or earlier communications from the examiner should be directed to Amanda C Walke whose telephone number is 571-272-1337. The examiner can normally be reached on M-R 5:30-4.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Cynthia Kelly can be reached on 571-272-1526. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Amanda C Walke Examiner

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ACW December 13, 2004